

Reliability Monitoring Results

Quarters: Q1/2023 to Q4/2023

Based on structural similarity

| Supplier | | User Part Number | | | | |
|--|---|-----------------------------|-----------|------------|-----------|--|
| Nexperia B.V. | | 74HCT594D | | | | |
| Part Description: 8-bit serial-in/parallel-out shift register with output storage register; TTL enabled | | | | | | |
| Function Family: HC(T) Process family: Super micron Package family: SO | | | | | | |
| JESD47 Test | Test Conditions | Duration | # Lots | # Quantity | # Rejects | |
| # 1 TEST Pre- and Post-Stress Electrical Test | Tamb = 25 °C | N/A | see below | all parts | see below | |
| # 2 PC Preconditioning | JESD22-A113 MSL 1 | N/A | 472 | 30095 | 0 | |
| # 5a HTOL EFR High Temperature Operating Life Extrinsic | JESD22-A108 Tj = 150°C VCCMAX ≤ V ≤ 1.2*VCCMAX | 48 hours or 168 hours | 67 | 24301 | 0 | |
| # 5b HTOL IFR High Temperature Operating Life Intrinsic | JESD22-A108 Tj = 150°C VCCMAX ≤ V ≤ 1.2*VCCMAX | ≥500 hours | 63 | 3580 | 0 | |
| # 7 TC Temperature Cycling | JESD22-A104 -65 °C to 150°C | ≥500 cycles | 75 | 17976 | 4 | |
| # 9 uHAST / HAST unbiased or biased High Accelerated Stress Test | JESD22-A101 Tamb = 130 °C, RH = 85%, V = VCCMAX | 96 hours | 208 | 12119 | 0 | |

Calculation of PPM, FIT and MTTF

Test considered for PPM calculation: High Temperature Operating LifeTest Extrinsic (HTOL EFR, Test # 5a above)

Test considered for FIT and MTTF calculations: High Temperature Operating LifeTest Intrinsic (HTOL IFR, Test # 5b above)

Confidence level 60%, derated to 55 °C, activation energy 0.7 eV, test time 168 to 1000 hours

| Product Family | Package Family | Quantity | Rejects | Extrinsic Failure Rate (PPM) | Intrinsic Failure Rate (FIT) | MTTF (hrs) |
|----------------|----------------|----------|---------|------------------------------|------------------------------|------------|
| HC(T) | SO | 3580 | 0 | 38 | 1.1 | 9.71 E+08 |